Application/Control No. Applicant(s)/Patent Under Reexamination 10/539,804 INOUE ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Jay M. Patidar 2862 **U.S. PATENT DOCUMENTS Document Number** Date Name Country Code-Number-Kind Code Classification MM-YYYY * Α US-5,382,900 A 01-1995 Hayashi, Yasukazu 324/207.23 US-5,696,444 A 12-1997 В Kipp et al. 324/207.23 US-2005/0121987 A1 С 06-2005 Ritzinger et al. 310/068.00B US-7,157,906 B2 D 01-2007 Miya, Taiichi 324/207.25 US-Ε US-F US-G US-Н US-US-J US-Κ US-L US-М FOREIGN PATENT DOCUMENTS **Document Number** Date Country Country Code-Number-Kind Code MM-YYYY Name Classification N 0 Р Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U

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